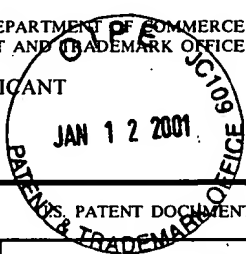


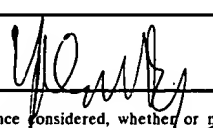
Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1518	SERIAL NO. 09/653,156
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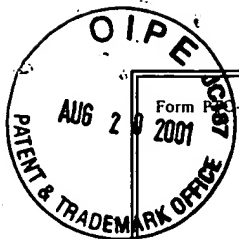
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<div style="font-size: 2em;">+</div> <div style="font-size: 2em;">91</div>	AA	09/653,149	Derderian			08/31/00
	AB	09/652,532	Derderian			08/31/00
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FOREIGN PATENT DOCUMENTS							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
<div style="font-size: 2em;">+</div>	AP		A.W. Ott, et al., "Atomic layer controlled deposition of Al ₂ O ₃ films using binary reaction sequence chemistry" Applied Surface Science (107) 1996, pps. 128-136.
	AQ		
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EXAMINER 	DATE CONSIDERED 11/17/07
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<i>h</i>	AA	6,180,481	01-2001	Deboer et al			
<i>h</i>	AB	6,218,256	04-2001	Agarwal			
<i>h</i>	AC	6,104,049	08-2000	Solayappan et al			
<i>h</i>	AD	6,180,447	01-2001	Park et al			
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Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
K	AA	6,274,428	08/2001	Wu			
	AB	6,124,158	09/2000	Dautartas et al			
	AC	6,144,060	11/2000	Park et al			
	AD	5,316,982	05/1994	Taniguchi			
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